FAIRCHILD

FDC855N

Single N-Channel, Logic Level, PowerTrench[®] MOSFET 30V, 6.1A, 27m Ω

Features

- Max $r_{DS(on)} = 27m\Omega$ at $V_{GS} = 10V$, $I_D = 6.1A$
- Max $r_{DS(on)} = 36m\Omega$ at $V_{GS} = 4.5V$, $I_D = 5.3A$
- SuperSOTTM -6 package: small footprint (72% smaller than standard SO-8; low profile (1mm thick).
- RoHS Compliant

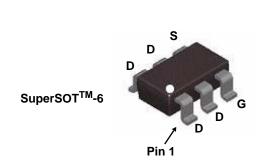


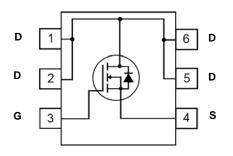
General Description

This N-Channel Logic Level MOSFET is an efficient solution for low voltage and battery powered applications. Utilizing Fairchild Semiconductor's advanced PowerTrench[®] process, this device possesses minimized on-state resistance to optimize the power consumption. They are ideal for applications where in-line power loss is critical.

Application

Power Management in Notebook, Hard Disk Drive





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V _{DS}	Drain to Source Voltage		30	V	
V _{GS}	Gate to Source Voltage		±20	V	
I _D	Drain Current -Continuous $T_A = 25^{\circ}C$	(Note 1a)	6.1		
	-Pulsed		20	Α	
P _D	Power Dissipation (Steady State)	(Note 1a)	1.6	W	
	Power Dissipation (Steady State)	(Note 1b)	0.8		
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C	
Thermal Ch	naracteristics				
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case (Note 1)		30	°C/W	
R_{\thetaJA}	Thermal Resistance, Junction to Ambient (No		78	C/VV	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
.855	FDC855N	SuperSOT-6	7"	8 mm	3000 units

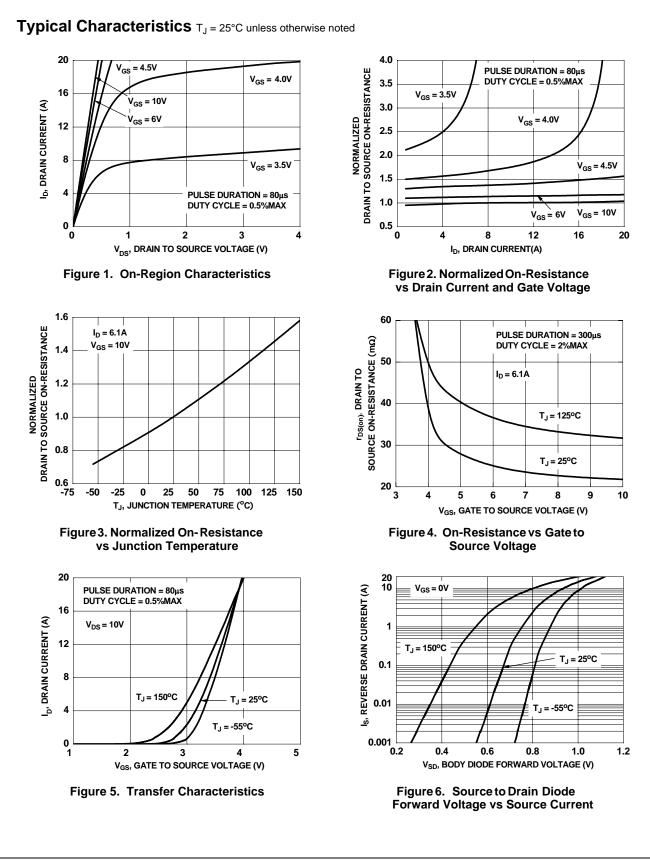
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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics			L	L	
BV _{DSS}	Drain to Source Breakdown Voltage	I _D = 250μA, V _{GS} = 0V	30			V
∆BV _{DSS}	Breakdown Voltage Temperature		00			
ΔT_J	Coefficient	$I_D = 250\mu A$, referenced to $25^{\circ}C$		24		mV/°C
	Zara Cata Valtaga Drain Current	$V_{GS} = 0V, V_{DS} = 24V,$			1	
DSS	Zero Gate Voltage Drain Current	T _C = 125°C			250	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA
On Chara	cteristics					
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.0	2.0	3.0	V
ΔV _{GS(th)}	Gate to Source Threshold Voltage		-			
ΔT_J	Temperature Coefficient	$I_D = 250\mu A$, referenced to 25°C		-6		mV/°C
		$V_{GS} = 10V, I_D = 6.1A$		20.7	27.0	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 5.3A$		28.2	36.0	mΩ
		$V_{GS} = 10V, I_D = 6.1A, T_J = 125^{\circ}C$		30.1	39.3	
9 _{FS}	Forward Transconductance	$V_{DD} = 10V, I_D = 6.1A$		20		S
Dynamic	Characteristics					
	Input Capacitance			493	655	pF
C _{oss}	Output Capacitance	— V _{DS} = 15V, V _{GS} = 0V,		108	145	pF
C _{rss}	Reverse Transfer Capacitance	f = 1MHz		62	95	pF
R _q	Gate Resistance	f = 1MHz		1.0		Ω
0		1 - 10012		1.0		32
Switching	Characteristics					
t _{d(on)}	Turn-On Delay Time			6	12	ns
t _r	Rise Time	$V_{DD} = 15V, I_D = 6.1A,$ $V_{GS} = 10V, R_{GEN} = 6\Omega$		2	10	ns
t _{d(off)}	Turn-Off Delay Time			14	23	ns
t _f	Fall Time			2	10	ns
Qg	Total Gate Charge at 10V	$V_{GS}=0Vto10V$		9.2	13	nC
Qg	Total Gate Charge at 5V	$V_{GS} = 0V \text{ to } 5V$ $V_{DD} = 15V,$ $I_D = 6.1A$		4.9	7.0	nC
Q _{gs}	Gate to Source Charge			1.7		nC
Q _{gd}	Gate to Drain "Miller" Charge			3.1		nC
Drain-Sou	Irce Diode Characteristics					
V _{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0V, I _S = 1.3A (Note 2)		0.80	1.2	V
t _{rr}	Reverse Recovery Time			17	31	ns
Q _{rr}	Reverse Recovery Charge	— I _F = 6.1A, di/dt = 100A/μs		6	12	nC
			b.	156°C/W whe	en mounted o	on a
	00000					

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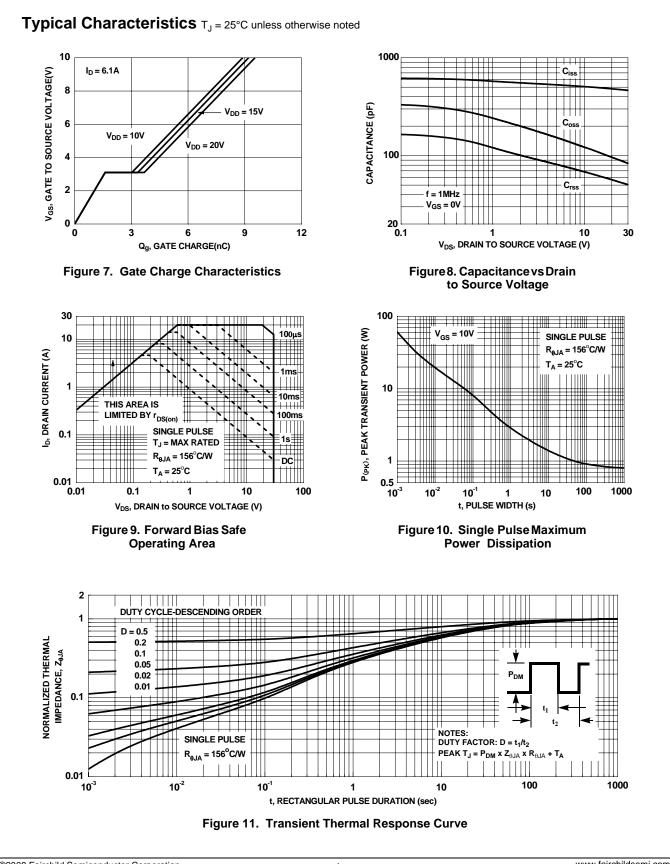
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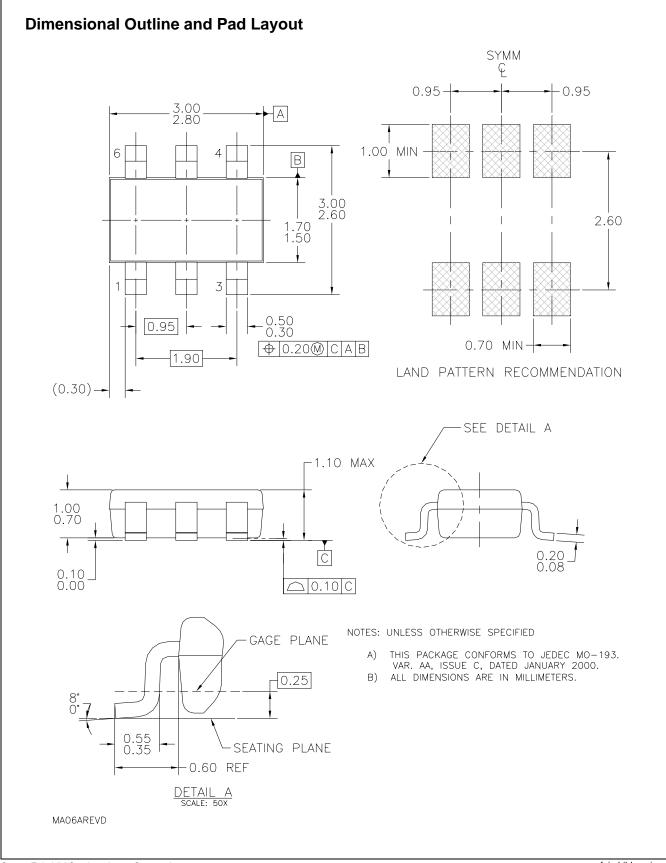
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